

CELADON

EXTENDED CAPABILITY VERSACORE™ SOLUTION

VC43™/VC43EAF™

Compatible with a Variety of Probing Platforms

The VC43™ Element Series VersaCore™ is modular and can be quickly and easily installed into a variety of industry compatible probing platforms including: MPPT, Verigy, P9000 or other custom solutions, including cabled-out interfaces. In addition to saving time, another advantage of the modularity is the ability to leave the interface in place and simply install the VC43™ topside using Celadon's tool-free twist and lock installation system which minimizes the possibility of triboelectric or interconnect issues that can occur during typical probe card changes.

The VC43™ can be used for production parametric test, modeling, characterization, and wafer level reliability testing. Cards can be configured up to 104 probes in either single or dual layer with near vertical probes to minimize scrub lengths on pads allowing the VC43™ to probe pads as small as 27µm.

Celadon's proven AttoFast™ technology has been integrated into the VC43™ probe card resulting in superior leakage performance, low and more stable capacitance while retaining the flexibility of a modular probe card system. The VC43EAF™ is an option offered as a sister product to the VC43E™. Both designs of the VC43™ are compatible with direct dock Parametric Testers and with cabled out solutions to support rack and stack testing.

Just like our VC20™ probe cards, Production customers are already achieving millions of touchdowns with the VC43™ resulting in exceptionally low cost of ownership. Email salesteam@celadonsystems.com for more information!



USE FOR **PRODUCTION PARAMETRIC TEST**,
MODELING, CHARACTERIZATION, & **WAFER LEVEL RELIABILITY TESTING**

